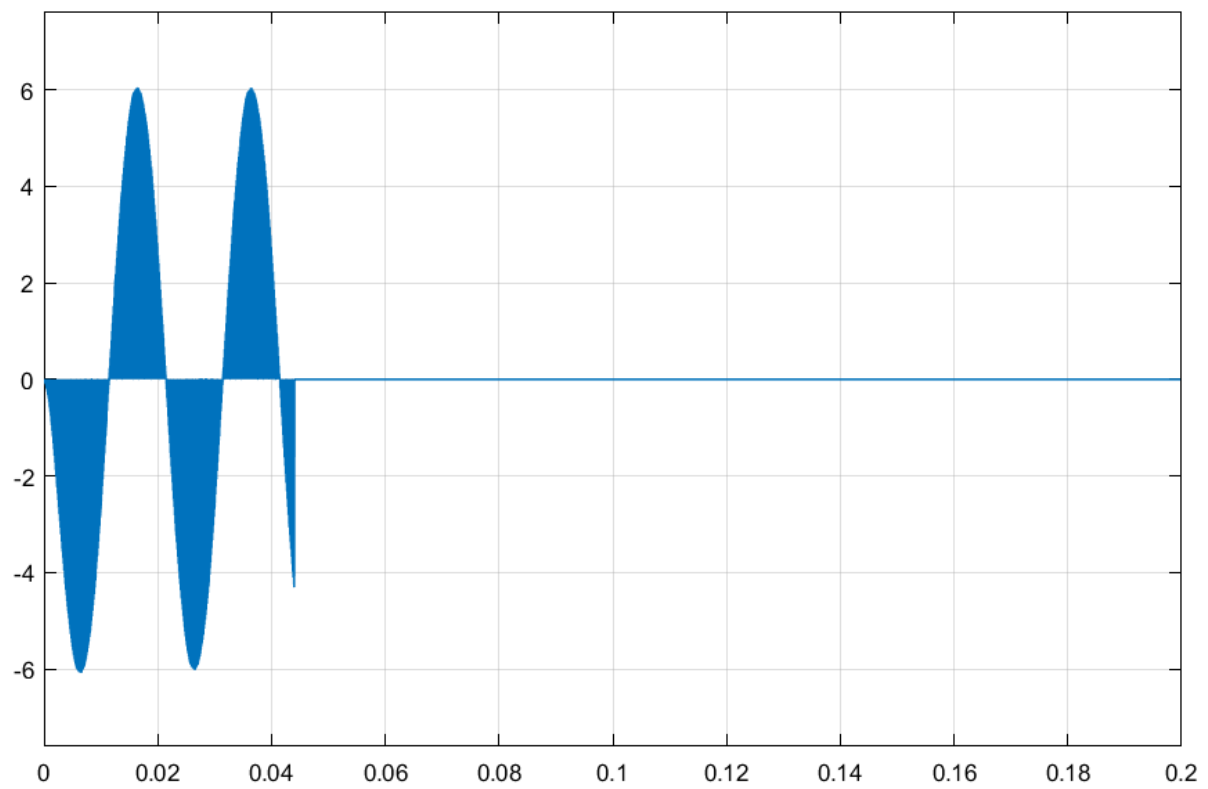
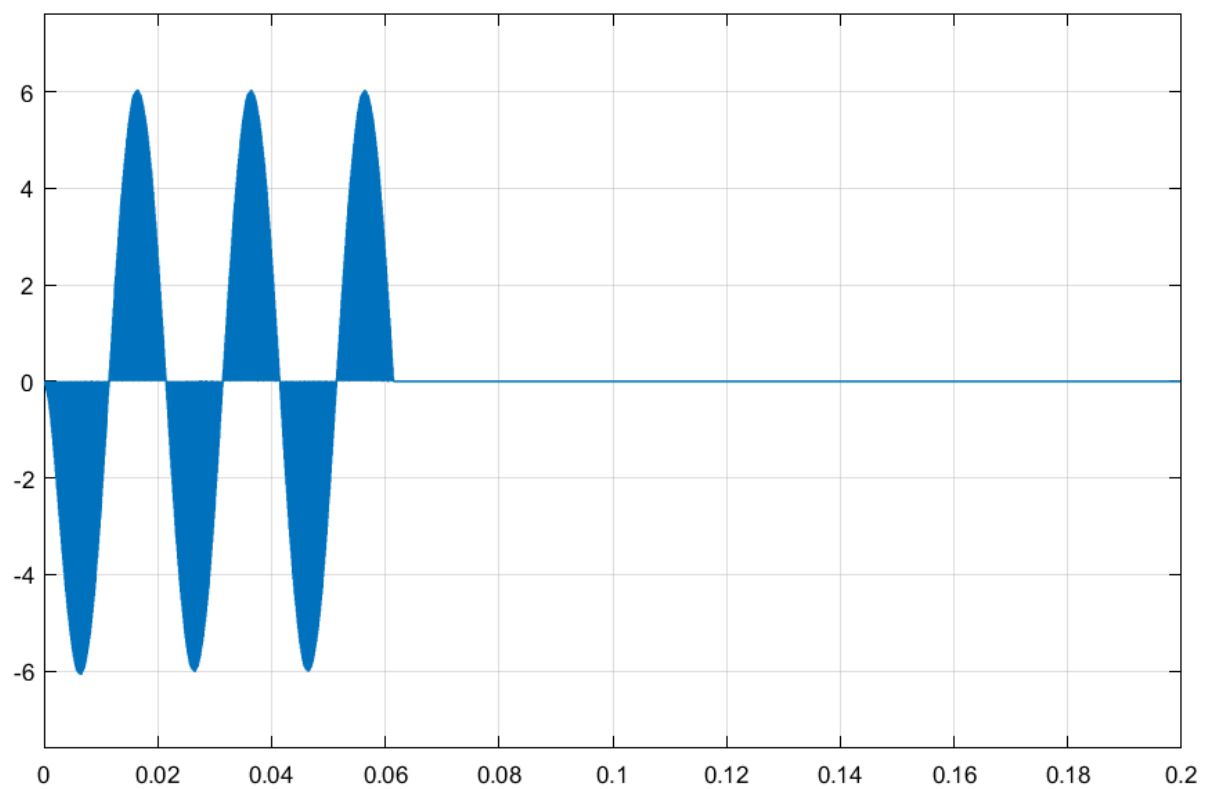
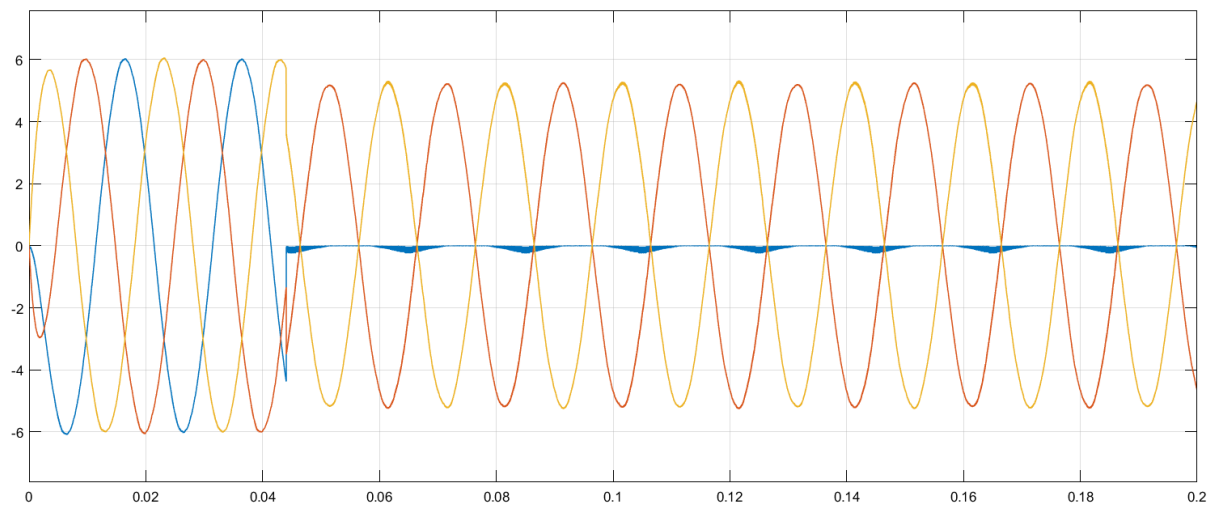


Fail at upper transistor while its conducting

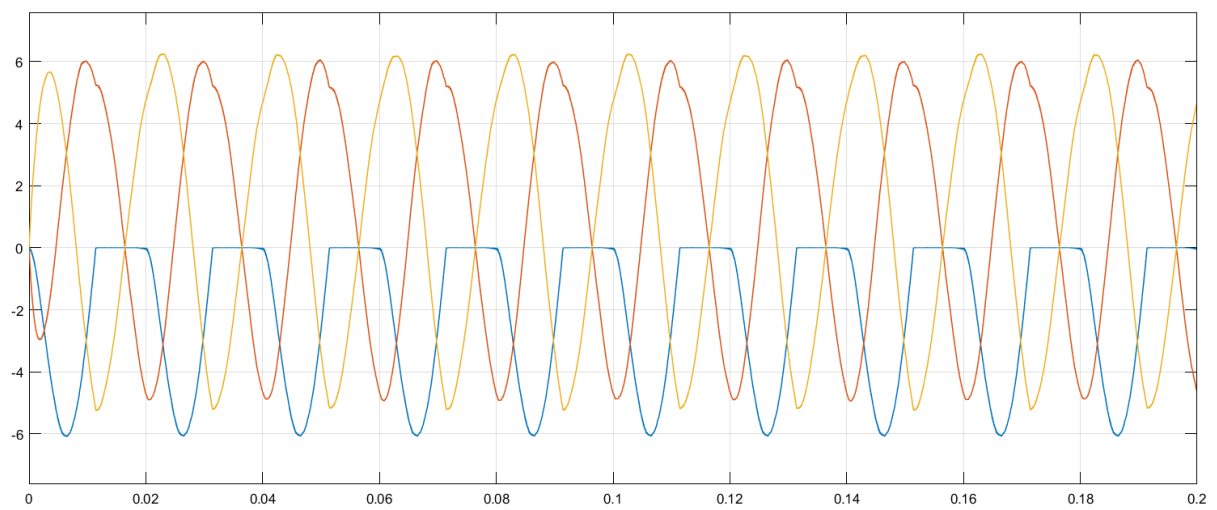


While its not conducting





When only mosfet part fails but diode conducts



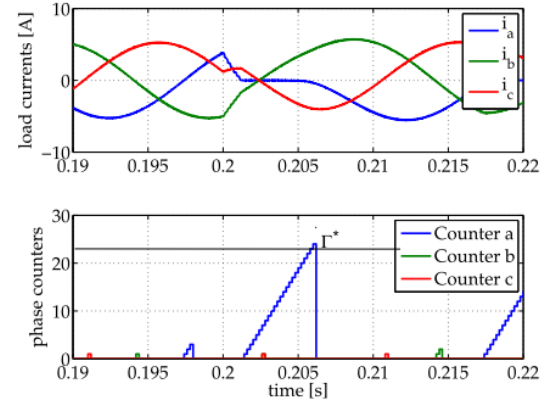
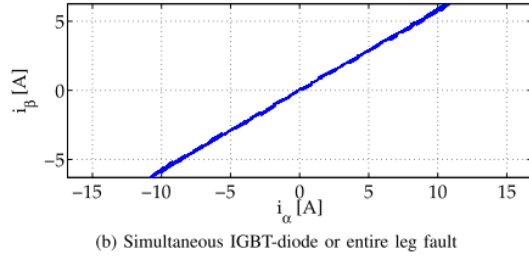
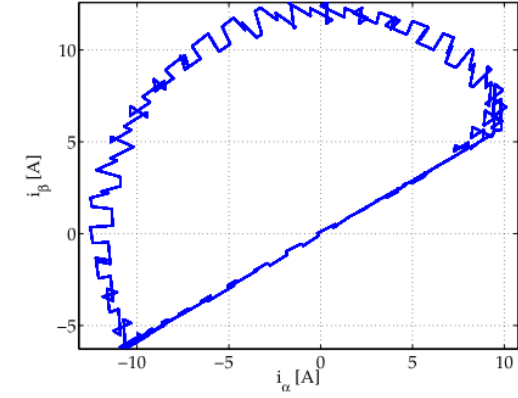


Fig. 4: Fault detection operating principle based on current samples counting.

relationship in (11) is satisfied within $\frac{2N}{\pi}\epsilon$ samples at most. Therefore, the diagnosis process can use a pulse counter operating with the same clock frequency used for current sampling. Such a counter is reset every time (11) are no longer verified. A fault index Γ much higher than $\frac{2N}{\pi}\epsilon$ is introduced.

Figure 4 shows the simulation of the diagnosis based on the sample counting principle. When (11) become true for each